

Notice of References Cited	Application/Control No. 10/524,177		Applicant(s)/Patent Under Reexamination VERMA ET AL.	
	Examiner Huy D. Nguyen		Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,920,814	07-1999	Sawyer et al.	455/422.1
*	B	US-6,853,851	02-2005	Rautiola et al.	455/553.1
*	C	US-5,713,073	01-1998	Warsta, Markus	455/524
*	D	US-2003/0112976	06-2003	Quick et al.	380/270
*	E	US-2002/0061746	05-2002	Jo et al.	455/433
*	E	US-6,810,250	10-2004	Jo et al.	455/433
*	G	US-6,690,798	02-2004	Dent, Paul W.	380/248
*	H	US-6,665,529	12-2003	Mills, Jr., James L.	455/411
*	I	US-6,553,227	04-2003	Ho et al.	455/433
*	J	US-5,375,251	12-1994	Pfundstein, Matthias	455/551
*	K	US-6,070,070	05-2000	Ladue, Christoph Karl	455/419
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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